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| <p>Search Notes</p>  | <p>Application/Control No.</p> <p>10695864</p> | <p>Applicant(s)/Patent Under Reexamination</p> <p>UESAKA ET AL.</p> |
| | <p>Examiner</p> <p>Al-Nazer, Leith A</p> | <p>Art Unit</p> <p>2821</p> |

| Notes | Date | Examiner |
|--|------------|-----------------------------|
| Updated EAST prior art text search (see "Examiner Search Notes") | 06/01/2006 | Leith Al-Nazer |
| EAST interference text search (see "Examiner Search Notes") | 06/01/2006 | Leith Al-Nazer |
| U.S. Patent and Trademark Office | | Part of Paper No.: 20060601 |

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| <p style="text-align: center;">Searched</p>  | <p>Application/Control No.</p> <p>10695864</p> | <p>Applicant(s)/Patent Under Reexamination</p> <p>UESAKA ET AL.</p> |
| | <p>Examiner</p> <p>Al-Nazer, Leith A</p> | <p>Art Unit</p> <p>2821</p> |

| Class | SubClass | Date | Examiner |
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| 343 | 703, 742, 832, 867 | 06/01/2006 | Leith Al-Nazer |

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| <i>Interference Searched</i>  | Application/Control No. 10695864 | Applicant(s)/Patent Under Reexamination UESAKA ET AL. |
| | Examiner Al-Nazer, Leith A | Art Unit 2821 |

| Class | SubClass | Date | Examiner |
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